

**Usage fees –  
NIMS Microstructural Characterization Platform  
(not including consumption tax)**

			Support type 1.Common use 2.Technical support 3.Technical surrogate 4. Collaborative study	Reservation per	Common use (yen/hour)			Technical support (yen/hour)			Technical surrogate & Collaborative study1 (yen/hour)			Technical surrogate & Collaborative study2 (yen/hour)			Technical surrogate & Collaborative study3 (yen/hour)		
					University /Public institution	smaller companies	Large companies	University /Public institution	smaller companies	Large companies	University /Public institution	smaller companies	Large companies	University /Public institution	smaller companies	Large companies	University /Public institution	smaller companies	Large companies
TEM	Real working environment physical characterization TEM (JEM-ARM200F-G)	Sengen	1,2,3,4	Session (3.5h)	4,000	8,000	12,000	6,100	12,200	18,300	6,310	12,620	18,930	8,200	16,400	24,600	10,300	20,600	30,900
TEM	Real working environmental electron holography microscope (JEM-ARM200F-B)	Sengen	1,2,3,4	Session (3.5h)	4,000	8,000	12,000	6,100	12,200	18,300	6,310	12,620	18,930	8,200	16,400	24,600	10,300	20,600	30,900
TEM	300kV transmission electron microscope (FEI Tecnai G2 F30)	Sengen	1,2,3,4	Session (3.5h)	4,000	8,000	12,000	6,100	12,200	18,300	6,310	12,620	18,930	8,200	16,400	24,600	10,300	20,600	30,900
TEM	200kV field emission transmission electron microscope (JEM-2100F1, JEM-2100F2)	Sengen	1,2,3,4	Session (3.5h)	2,000	4,000	6,000	4,100	8,200	12,300	4,310	8,620	12,930	6,200	12,400	18,600	8,300	16,600	24,900
TEM	200kV transmission electron microscope (JEM-2100)	Sengen	1,2,3,4	Session (3.5h)	1,000	2,000	3,000	3,100	6,200	9,300	3,310	6,620	9,930	5,200	10,400	15,600	7,300	14,600	21,900
TEM	Field emission scanning electron microscope (JSM-7000F)	Sengen	1,2,3,4	Session (3.5h)	1,000	2,000	3,000	3,100	6,200	9,300	3,310	6,620	9,930	5,200	10,400	15,600	7,300	14,600	21,900
TEM	Focused Ion Beam systems (JIB-4000, JEM-9320FIB, JEM-9310FIB1, JEM-9310FIB2)	Sengen	1,2,3,4	Session (3.5h)	1,000	2,000	3,000	3,100	6,200	9,300	3,310	6,620	9,930	5,200	10,400	15,600	7,300	14,600	21,900
TEM	Dual beam system(NB5000)	Sengen	1,2,3,4	Session (3.5h)	3,000	6,000	9,000	5,100	10,200	15,300	5,310	10,620	15,930	7,200	14,400	21,600	9,300	18,600	27,900
TEM	Pickup system *Available in 15 minuteincrements	Sengen	1,2,3,4	Hour(1h)	1,000	2,000	3,000	3,100	6,200	9,300	3,310	6,620	9,930	5,200	10,400	15,600	7,300	14,600	21,900
TEM	TEM sample preparation apparatus	Sengen	1,2,3,4	Hour(1h)	1,000	2,000	3,000	3,100	6,200	9,300	3,310	6,620	9,930	5,200	10,400	15,600	7,300	14,600	21,900
TEM	Ultramicrotome (Leica EM UC6)	Sengen	2,3,4	Hour(1h)	-	-	-	3,100	6,200	9,300	3,310	6,620	9,930	5,200	10,400	15,600	7,300	14,600	21,900
TEM	HRTEM Analysis system	Sengen	2,3,4	Hour(1h)	-	-	-	3,100	6,200	9,300	3,310	6,620	9,930	5,200	10,400	15,600	7,300	14,600	21,900
TEM	Electron tomography analysis system	Sengen	2,3,4	Hour(1h)	-	-	-	3,100	6,200	9,300	3,310	6,620	9,930	5,200	10,400	15,600	7,300	14,600	21,900

## [Other]

TEM	Date analysis *Available in 15 minuteincrements	Sengen	Technical Surrogate	Hour(1h)	-	-	-	-	-	-	2,100	4,200	6,300	-	-	-	-	-	-
TEM	Technical guidance fee *Available in 15 minuteincrements	Sengen	Technical support	Hour(1h)	-	-	-	2,100	4,200	6,300	-	-	-	-	-	-	-	-	-

※The setting of the fee for "Technical Surrogate" is divided into 3 types according to the difficulty level. The level 2 applies to standard operations.